

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

**In re application of:** Rajski et al.

**Application No.** Not yet assigned

**Filed:** February 17, 2004

**Confirmation No.** --

**For:** METHOD FOR SYNTHESIZING LINEAR  
FINITE STATE MACHINES

**Examiner:** --

**Art Unit:** --

**Attorney Reference No.** 1011-67627

MAIL STOP PATENT APPLICATION  
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**INFORMATION DISCLOSURE STATEMENT**  
**FOR CONTINUING APPLICATIONS**

Listed on the accompanying form PTO-1449 are several English-language documents. Applicants respectfully request that such documents be listed as references cited on the issued patent.

The present application relies upon U.S. Patent Application No. 10/346,699, filed January 16, 2003, which is a continuation of U.S. Application No. 09/957,701, filed September 18, 2001, which is a continuation of U.S. Application No. 09/620,023, filed July 20, 2000, which claims the benefit of U.S. Provisional Application No. 60/167,455, filed November 23, 1999, for an earlier filing date under 35 U.S.C. § 120. Furthermore, documents listed on the accompanying form PTO-1449 were disclosed to or cited by the Patent Office in the earlier U.S. application.

Copies of the documents listed on the accompanying form PTO-1449 that were cited by

or submitted to the Patent Office in the earlier application need not be sent to the Patent Office pursuant to 37 C.F.R. § 1.98. However, applicants will furnish the Patent Office with such copies upon request.

The filing of this Information Disclosure Statement shall not be construed to be an admission that the information cited in the statement is, or is considered to be, prior art or otherwise material to patentability as defined in 37 C.F.R. §1.56.

Respectfully submitted,

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<b>U.S. PATENT DOCUMENTS</b>					
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